AMENDMENTS TO THE CLAIMS

The following is a complete, marked-up listing of revised claims with a status identifier in parenthesis, underlined text indicating insertions, and strike through and/or double-bracketed text indicating deletions.

LISTING OF CLAIMS

1-8. (Cancelled).

9. (Previously Presented) A pore or particle-size distribution measurement method for measuring size distribution of pores or particles existing within a porous insulator film formed on a surface of a substrate, comprising:

irradiating the insulator film with X-rays from the insulator film's surface side at an incident angle which is set to be larger than a total-reflection critical angle of the insulator film and larger than 1.0 times a total-reflection critical angle of the substrate but less than 1.3 times a total-reflection critical angle of the substrate; and

detecting among reflection components reflected on the surface of the substrate of the X-rays which have entered the insulator film, reflection components exiting from the insulator film after entering the pore or particle and scattering, having an exit angle larger than that of reflection components which exit from the insulator film without entering the pore or particle.

10. (Previously Presented) The pore or particle-size distribution measurement method of claim 9, wherein the X-rays are generated by a line focus X-ray tube, and a parallel light flux, of the generated X-rays, composed of mutually-parallel components of a specific direction lying in a specific wavelength band is selected to enter the measurement target object at the incident angle,

and wherein only a specific-direction component of the X-rays coming from the measurement target object is allowed to pass through a slit, and the X-rays having passed through the slit is detected by a position-sensitive X-ray detector.

11. (Previously Presented) The pore or particle-size distribution measurement method of claim 9, wherein the X-rays are generated by a point focus X-ray tube, and an X-ray beam, of the generated X-rays, composed of specific-direction components which are mutually parallel and exist in a specific wavelength band is selected to enter the measurement target object at the incident angle,

and wherein the X-rays coming from the measurement target object are detected by a position-sensitive X-ray detector.

12. (Previously Presented) The pore or particle-size distribution measurement method of claim 10, wherein a specific specular reflection component is prevented from entering a detection surface of the position-

sensitive X-ray detector by an X-ray blocking plate, the specular reflection component being derived from the X-rays which are reflected from the surface of the substrate after having entered the insulator film and exited from the insulator film without entering the pore or particle.

13. (Previously Presented) The pore or particle-size distribution measurement method of claim 9, wherein the X-rays are generated by an X-ray generating source and the generated X-rays are converged and made incident onto the measurement target object at the incident angle,

and wherein the X-rays coming from the measurement target object are detected by a position-sensitive X-ray detector.

14. (Previously Presented) The pore or particle-size distribution measurement method of claim 13, wherein an area of incident of the X-rays on the measurement target object is regulated by an X-ray irradiation range regulatory plate that is arranged immediately above a position of incidence at a predetermined spacing.

15. (Cancelled).

16. (Previously Presented) The pore or particle-size distribution measurement method of claim 11, wherein a specific specular reflection component is prevented from entering a detection surface of the position-

sensitive X-ray detector by an X-ray blocking plate, the specular reflection component being derived from the X-rays which are reflected from the surface of the substrate after having entered the insulator film and exited from the insulator film without entering the pore or particle.

*** END CLAIM LISTING ***